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Charles A. Bouman
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Contents

vii *Conference Committee*
ix *Keynote Presentation Slide Information*

SESSION 1 SPECIAL SESSION ON MICROPSCOPY AND INFORMATION MODELING

8296 06 **Image sequence segmentation combining global labeling and local relabeling and its application to materials science images** [8296-04]
J. W. Waggoner, Univ. of South Carolina (United States); J. Simmons, Air Force Research Lab. (United States); S. Wang, Univ. of South Carolina (United States)

8296 08 **Computer-aided fiber analysis for crime scene forensics** [8296-06]
M. Hildebrandt, Otto-von-Guericke-Univ. of Magdeburg (Germany); C. Arndt, Brandenburg Univ. of Applied Sciences (Germany); A. Makrushin, Otto-von-Guericke-Univ. of Magdeburg (Germany) and Brandenburg Univ. of Applied Sciences (Germany); J. Dittmann, Otto-von-Guericke-Univ. of Magdeburg (Germany)

8296 0A **3D reconstruction based on single-particle cryo electron microscopy images as a random signal in noise problem** [8296-08]
Q. Wang, Cornell Univ. (United States); Y. Zheng, Lawrence Berkeley National Lab. (United States); P. C. Doerschuk, Cornell Univ. (United States)

8296 0B **Highly scalable methods for exploiting a label with unknown location in order to orient a set of single-particle cryo electron microscopy images** [8296-09]
C. J. Prust, Milwaukee School of Engineering (United States); Q. Wang, P. C. Doerschuk, Cornell Univ. (United States); J. E. Johnson, The Scripps Research Institute (United States)

SESSION 2 RECONSTRUCTION

8296 0D **Image reconstruction using projections from a few views by discrete steering combined with DART** [8296-11]
J. Kwon, S. M. Song, B. Kauke, D. P. Boyd, TeleSecurity Sciences, Inc. (United States)

8296 0E **One-dimensional control grid interpolation-based demosaicing and color image interpolation** [8296-12]
C. M. Zwart, D. H. Frakes, Arizona State Univ. (United States)

8296 0F **Limited view angle iterative CT reconstruction** [8296-13]
S. J. Kisner, E. Haneda, C. A. Bouman, Purdue Univ. (United States); S. Skatter, M. Kourinny, Morpho Detection, Inc. (United States); S. Bedford, Astrophysics, Inc. (United States)

8296 0G **Variational semi-blind sparse image reconstruction with application to MRFM** [8296-15]
S. U. Park, Univ. of Michigan (United States); N. Dobigeon, Univ. of Toulouse (France); A. O. Hero, Univ. of Michigan (United States)

SESSION 3 CLASSIFICATION AND DETECTION

8296 0H **Moon search algorithms for NASA's Dawn Mission to asteroid Vesta** [8296-16]
N. Memarsadeghi, L. A. McFadden, D. R. Skillman, NASA Goddard Space Flight Ctr. (United States); B. McLean, M. Mutchler, Space Telescope Science Institute (United States); U. Carsenty, DLR, Institute of the Planetary Research (Germany); E. E. Palmer, Planetary Science Institute (United States)

8296 0K **Multichannel hierarchical image classification using multivariate copulas** [8296-19]
A. Voisin, V. A. Krylov, INRIA Sophia Antipolis Méditerranée (France); G. Moser, S. B. Serpico, Univ. of Genoa (Italy); J. Zerubia, INRIA Sophia Antipolis Méditerranée (France)

SESSION 4 ENHANCEMENT, DENOISING, AND RESTORATION I

8296 0M **Denoising and deblurring of Fourier transform infrared spectroscopic imaging data** [8296-20]
T. H. Nguyen, R. K. Reddy, M. J. Walsh, M. Schulmerich, G. Popescu, M. N. Do, R. Bhargava, Univ. of Illinois at Urbana-Champaign (United States)

8296 0N **Iterative weighted risk estimation for nonlinear image restoration with analysis priors** [8296-21]
S. Ramani, J. Rosen, Z. Liu, J. A. Fessler, Univ. of Michigan (United States)

8296 0O **Nonlocal transform-domain denoising of volumetric data with groupwise adaptive variance estimation** [8296-22]
M. Maggioni, A. Foi, Tampere Univ. of Technology (Finland)

8296 0P **Non-uniform contrast and noise correction for coded source neutron imaging** [8296-23]
H. J. Santos-Villalobos, P. R. Bingham, Oak Ridge National Lab. (United States)

8296 0Q **Image enhancement and quality measures for dietary assessment using mobile devices** [8296-24]
C. Xu, F. Zhu, N. Khanna, Purdue Univ. (United States); C. J. Boushey, Purdue Univ. (United States) and Univ. of Hawaii Cancer Ctr. (United States); E. J. Delp, Purdue Univ. (United States)

SESSION 5 ENHANCEMENT, DENOISING, AND RESTORATION II

8296 0S **Subjective evaluations of example-based, total variation, and joint regularization for image processing** [8296-26]
H. S. Anderson, Sandia National Labs. (United States); M. R. Gupta, Univ. of Washington (United States); J. Hardeberg, Gjøvik Univ. (Norway)

8296 0T **Removal of haze and noise from a single image** [8296-27]
E. Matlin, P. Milanfar, Univ. of California, Santa Cruz (United States)

SESSION 6 COMPUTER VISION AND 3D MODELING

8296 0U **Finding saliency in noisy images** [8296-28]
C. Kim, P. Milanfar, Univ. of California, Santa Cruz (United States)

8296 0V **Automatic loop closure detection using multiple cameras for 3D indoor localization** [8296-29]
J. Kua, N. Corso, A. Zakhor, Univ. of California, Berkeley (United States)

8296 0W **An information theoretic trackability measure** [8296-30]
S. T. Acton, A. Aksel, Univ. of Virginia (United States)

8296 0X **Text replacement on cylindrical surfaces: a semi-automatic approach** [8296-31]
H. Ding, R. Bala, Z. Fan, Xerox Corp. (United States); C. A. Bouman, J. P. Allebach, Purdue Univ. (United States)

8296 0Z **Registration and integration of multiple depth images using signed distance function** [8296-42]
D. B. Kubacki, H. Q. Bui, S. D. Babacan, M. N. Do, Univ. of Illinois at Urbana-Champaign (United States)

8296 10 **Image reconstruction from nonuniformly spaced samples in Fourier domain optical coherence tomography** [8296-14]
J. Ke, R. Zhu, E. Y. Lam, The Univ. of Hong Kong (Hong Kong, China)

INTERACTIVE PAPER SESSION

8296 11 **Analysis of the practical coverage of uniform motions to approximate real camera shakes** [8296-33]
H. Cho, S. Cho, POSTECH (Korea, Republic of); Y. S. Moon, J. Cho, S. Lee, Samsung Electronics Co., Ltd. (Korea, Republic of); S. Lee, POSTECH (Korea, Republic of)

8296 12 **Real-time computational camera system for high-sensitivity imaging by using combined long/short exposure** [8296-34]
S. Sato, Y. Okada, T. Azuma, Panasonic Corp. (Japan)

8296 13 **Color correction with edge preserving and minimal SNR decrease using multi-layer decomposition** [8296-35]
B. K. Park, W. Choe, J. Lim, S. Lee, C. Kim, Samsung Electronics Co., Ltd. (Korea, Republic of)

8296 14 **Bayesian image superresolution for hyperspectral image reconstruction** [8296-36]
Y. Murayama, A. Ide-Ektessabi, Kyoto Univ. (Japan)

8296 15 **ToF depth image motion blur detection using 3D blur shape models** [8296-37]
S. Lee, H. Shim, J. D. K. Kim, C. Y. Kim, Samsung Advanced Institute of Technology (Korea, Republic of)

8296 16 **Computational imaging of defects in commercial substrates for electronic and photonic devices** [8296-38]
M. Fukuzawa, R. Kashiwagi, M. Yamada, Kyoto Institute of Technology (Japan)

8296 17 **Nondestructive three-dimensional measurement of gas temperature distribution by phase tomography** [8296-39]
S. Tomioka, S. Nishiyama, Hokkaido Univ. (Japan)

8296 18 **Closed-form inverses for the mixed pixel/multipath interference problem in AMCW lidar** [8296-40]
J. P. Godbaz, M. J. Cree, A. A. Dorrington, Univ. of Waikato (New Zealand)

Author Index

Conference Committee

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Keynote Presentation
Charles A. Bouman, Purdue University (United States)

1 Special Session on Micropscopy and Information Modeling
Charles A. Bouman, Purdue University (United States)

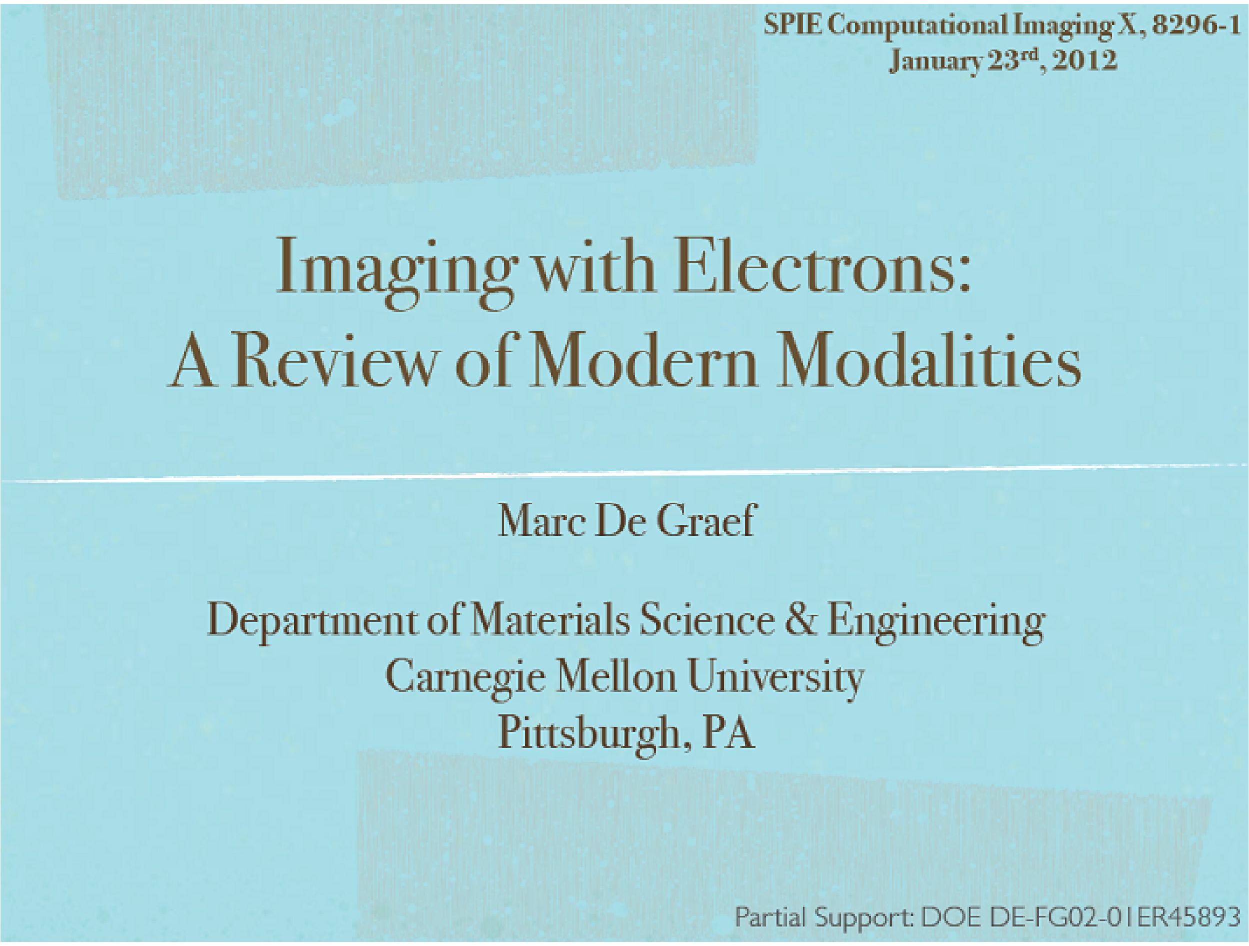
2 Reconstruction
Charles A. Bouman, Purdue University (United States)

3 Classification and Detection
Charles A. Bouman, Purdue University (United States)

4 Enhancement, Denoising, and Restoration I
Charles A. Bouman, Purdue University (United States)

5 Enhancement, Denoising, and Restoration II
Charles A. Bouman, Purdue University (United States)

6 Computer Vision and 3D Modeling
Charles A. Bouman, Purdue University (United States)



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Imaging with Electrons: A Review of Modern Modalities

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